References

- [1] Rainer Waser and Masakazu Aono. Nanoionics-based resistive switching memories. *Nat Mater*, 6(11):833–840, 2007.
- [2] Y. Zhang, A. M. Schultz, H. Chien L. Li, P. Salvador, and G. Rohrer. Combinatorial substrate epitaxy: A high throughput method for determining phase and orientation relationships and its application to BiFeO₃/TiO₂ heterostructures. *Acta Mater*, page in review (http://neon.materials.cmu.edu/rohrer/papers/pre_20 12_05.pdf), 2012.
- [3] J. Aarik, A. Aidla, V. Sammelselg, and T. Uustare. Effect of growth conditions on formation of TiO₂-II thin films in atomic layer deposition process. *Journal of Crystal Growth*, 181(3):259–264, 1997.
- [4] B. L. Adams, S. I. Wright, and K. Kunze. Orientation imaging the emergence of a new microscopy. *Metallurgical Transactions a-Physical Metallurgy and Materials Science*, 24(4):819–831, 1993.
- [5] F. Calle-Vallejo, J. I. Martinez, J. M. Garcia-Lastra, M. Mogensen, and J. Rossmeisl. Trends in stability of perovskite oxides. *Angewandte Chemie-International Edition*, 49(42):7699–7701, 2010. doi:10.1002/anie.201002301.
- [6] Joseé C. Conesa. The relevance of dispersion interactions for the stability of oxide phases. The Journal of Physical Chemistry C, 114(51):22718– 22726, 2010. doi:10.1021/jp109105g.
- [7] J Haines, JM Léger, and G Bocquillon. Synthesis and design of superhard materials. *Annual Review of Materials Research*, 31(1):1–23, 2001. doi:10.1146/annurev.matsci.31.1.1.
- [8] K. De Keyser, C. Detavernier, and R. L. Van Meirhaeghe. Characterization of the texture of silicide films using electron backscattered diffraction. *Applied Physics Letters*, 90(12), 2007. doi:10.1063/1.2716362.